

Search Notes

Application/Control No.

10/507,466

Examiner

Shin-Lin Chen

Applicant(s)/Patent under
Reexamination

OSTERMEIER, MARC

Art Unit

1632

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
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